Substitute for form 1449/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

| Sheet | 1 | of | 2 |

Complete if Known

Application Number	10/630,615
Filing Date	07/30/2003
First Named Inventor	Josey G. Angilivelil
Art Unit	2825
Examiner Name	NGHIA M. DOAN
Attorney Docket Number	TI-34945

U. S. PATENT DOCUMENTS

Examiner Initials*	Cite No.[1]	Document Number Number-Kind Code[2] *(if known)*	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
NMD		US- 5,606,567	02/25/1997	Agrawal, et al.	
NMD		US- 6,131,181	10/10/2000	Bushnell, et al.	
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FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.[1]	Foreign Patent Document Country Code[3] Number[4] Kind Code[5] *(if known)*	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	T[6]

| Examiner Signature | *[signature]* | Date Considered | 11/28/05 |

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. [1] Applicant's unique citation designation number (optional). [2] See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. [3] Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). [4] For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. [5] Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. [6] Applicant is to place a check mark here if English language Translation is attached.

Substitute for form 1449/PTO	Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT *(Use as many sheets as necessary)*	Application Numb r	101630,615
	Filing Date	07/30/2003
	First Nam d Inventor	Josey G. Angilivelil
	Art Unit	2825
	Examiner Name	NGHIA M. DOAN
Sheet	2	of	2	Attorney Docket Number	TI-34945

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.[1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T^2
NMD		SAMY R. MAKAR and EDWARD J. MCCLUSKEY, "Iddq Test Pattern Generation for Scan Chain Latches and Flip-Flops", Center for Reliable Computing Standford University, (date unknown)	
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Examiner Signature		Date Considered	11/28/03